

April 2000

FQA12N60

600V N-Channel MOSFET

General Description

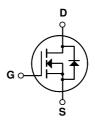
These N-Channel enhancement mode power field effect transistors are produced using Fairchild's proprietary, planar stripe, DMOS technology.

This advanced technology has been especially tailored to minimize on-state resistance, provide superior switching performance, and withstand high energy pulse in the avalanche and commutation mode. These devices are well suited for high efficiency switch mode power supply.

Features

- 12A, 600V, R_{DS(on)} = 0.7 Ω @ V_{GS} = 10 V Low gate charge (typical 42 nC)
- Low Crss (typical 25 pF)
- · Fast switching
- 100% avalanche tested
- · Improved dv/dt capability





Absolute Maximum Ratings $T_C = 25$ °C unless otherwise noted

Symbol	Parameter		FQA12N60	Units	
V _{DSS}	Drain-Source Voltage		600	V	
I _D	Drain Current - Continuous (T _C = 25°C	C)	12	Α	
	- Continuous (T _C = 100	°C)	7.6	Α	
I _{DM}	Drain Current - Pulsed	(Note 1)	48	А	
V _{GSS}	Gate-Source Voltage		± 30	V	
E _{AS}	Single Pulsed Avalanche Energy	(Note 2)	790	mJ	
I _{AR}	Avalanche Current	(Note 1)	12	Α	
E _{AR}	Repetitive Avalanche Energy	(Note 1)	24	mJ	
dv/dt	Peak Diode Recovery dv/dt	(Note 3)	4.5	V/ns	
P _D	Power Dissipation (T _C = 25°C)		240	W	
	- Derate above 25°C		1.92	W/°C	
T _J , T _{STG}	Operating and Storage Temperature Range		-55 to +150	°C	
T _L	Maximum lead temperature for soldering purposes, 1/8" from case for 5 seconds		300	°C	

Thermal Characteristics

Symbol	Parameter	Тур	Max	Units
$R_{\theta JC}$	Thermal Resistance, Junction-to-Case		0.52	°C/W
$R_{\theta CS}$	Thermal Resistance, Case-to-Sink	0.24		°C/W
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient		40	°C/W

Symbol	Parameter	Test Conditions	Min	Тур	Max	Units
Off Cha	aracteristics					
BV _{DSS}	Drain-Source Breakdown Voltage	$V_{GS} = 0 \text{ V}, I_D = 250 \mu\text{A}$	600			V
ΔBV _{DSS} / ΔT _J	Breakdown Voltage Temperature Coefficient	$I_D = 250 \mu A$, Referenced to 25°C		0.71		V/°C
I _{DSS}	Zero Gate Voltage Drain Current	V _{DS} = 600 V, V _{GS} = 0 V			10	μΑ
		V _{DS} = 480 V, T _C = 125°C			100	μΑ
I _{GSSF}	Gate-Body Leakage Current, Forward	V _{GS} = 30 V, V _{DS} = 0 V			100	nA
I _{GSSR}	Gate-Body Leakage Current, Reverse	$V_{GS} = -30 \text{ V}, V_{DS} = 0 \text{ V}$			-100	nA
On Cha	aracteristics					
V _{GS(th)}	Gate Threshold Voltage	$V_{DS} = V_{GS}, I_{D} = 250 \mu\text{A}$	3.0		5.0	V
R _{DS(on)}	Static Drain-Source On-Resistance	V _{GS} = 10 V, I _D = 6.0 A		0.55	0.7	Ω
9 _{FS}	Forward Transconductance	$V_{DS} = 50 \text{ V}, I_D = 6.0 \text{ A}$ (Note 4)		11		S
C _{iss}	Input Capacitance Output Capacitance	V _{DS} = 25 V, V _{GS} = 0 V, f = 1.0 MHz		1480 200	1900 270	pF pF
C _{rss}	Reverse Transfer Capacitance	1 = 1.0 MHZ		25	35	рF
-133						P.
Switch	ing Characteristics					
t _{d(on)}	Turn-On Delay Time	V _{DD} = 300 V, I _D = 12 A,		30	70	ns
t _r	Turn-On Rise Time	$R_G = 25 \Omega$		115	240	ns
t _{d(off)}	Turn-Off Delay Time			95	200	ns
t _f	Turn-Off Fall Time	(Note 4, 5)		85	180	ns
Qg	Total Gate Charge	$V_{DS} = 480 \text{ V}, I_D = 12 \text{ A},$		42	54	nC
Q _{gs}	Gate-Source Charge	V _{GS} = 10 V		8.6		nC
Q_{gd}	Gate-Drain Charge	(Note 4, 5)		21		nC
		ad Maximum Patings				
Drain-S	Cource Diede Characterietice au					
	Source Diode Characteristics as Maximum Continuous Drain-Source Dio				12	Α
I _S	Maximum Continuous Drain-Source Dic	ode Forward Current			12 48	A A
I _S		ode Forward Current Forward Current				
I _S	Maximum Continuous Drain-Source Did Maximum Pulsed Drain-Source Diode F	ode Forward Current			48	Α

- **Notes:**1. Repetitive Rating : Pulse width limited by maximum junction temperature 2. L = 10mH, $I_{AS} = 12A$, $V_{DD} = 50V$, $R_G = 25 \Omega$, Starting $T_J = 25^{\circ}C$ 3. $I_{SD} \le 12A$, I_{J} di/dt $\le 200A/\mu$ s, $V_{DD} \le BV_{DSS}$, Starting $T_J = 25^{\circ}C$ 4. Pulse Test : Pulse width $\le 300\mu$ s, Duty cycle $\le 2\%$ 5. Essentially independent of operating temperature

Typical Characteristics

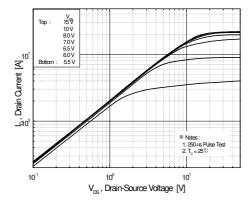


Figure 1. On-Region Characteristics

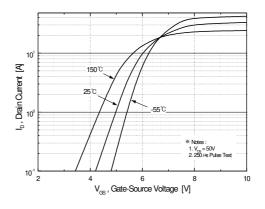


Figure 2. Transfer Characteristics

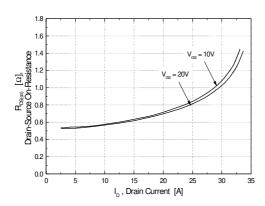


Figure 3. On-Resistance Variation vs. Drain Current and Gate Voltage

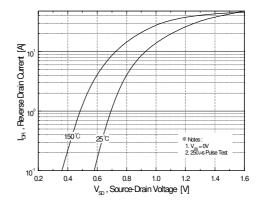


Figure 4. Body Diode Forward Voltage Variation vs. Source Current and Temperature

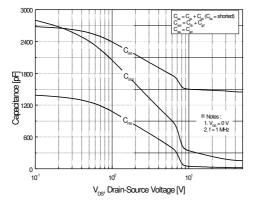


Figure 5. Capacitance Characteristics

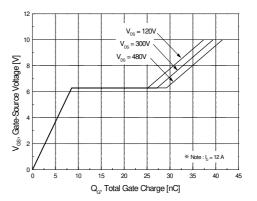
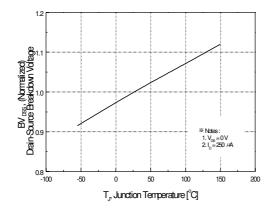


Figure 6. Gate Charge Characteristics

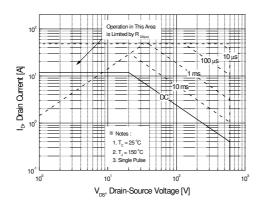
Typical Characteristics (Continued)



3.0 2.5 (Soziama) 2.5 (Soziama

Figure 7. Breakdown Voltage Variation vs. Temperature

Figure 8. On-Resistance Variation vs. Temperature



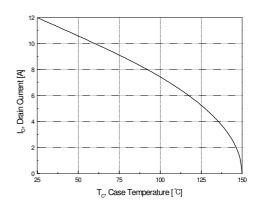


Figure 9. Maximum Safe Operating Area

Figure 10. Maximum Drain Current vs. Case Temperature

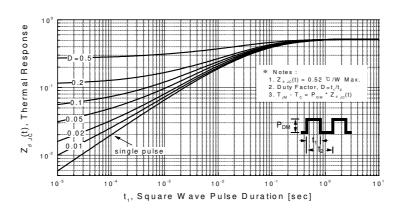
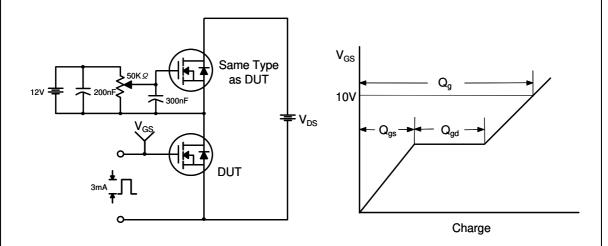


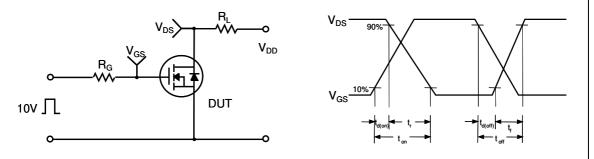
Figure 11. Transient Thermal Response Curve

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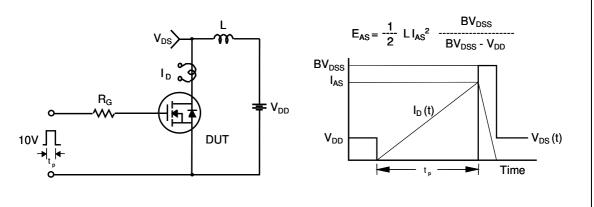
Gate Charge Test Circuit & Waveform



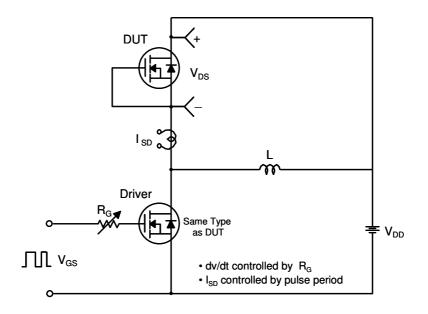
Resistive Switching Test Circuit & Waveforms

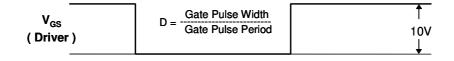


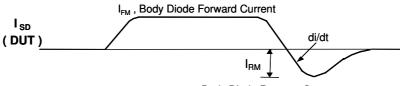
Unclamped Inductive Switching Test Circuit & Waveforms



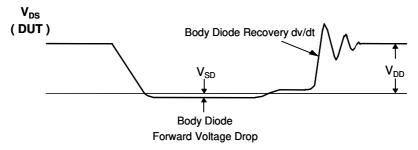
Peak Diode Recovery dv/dt Test Circuit & Waveforms



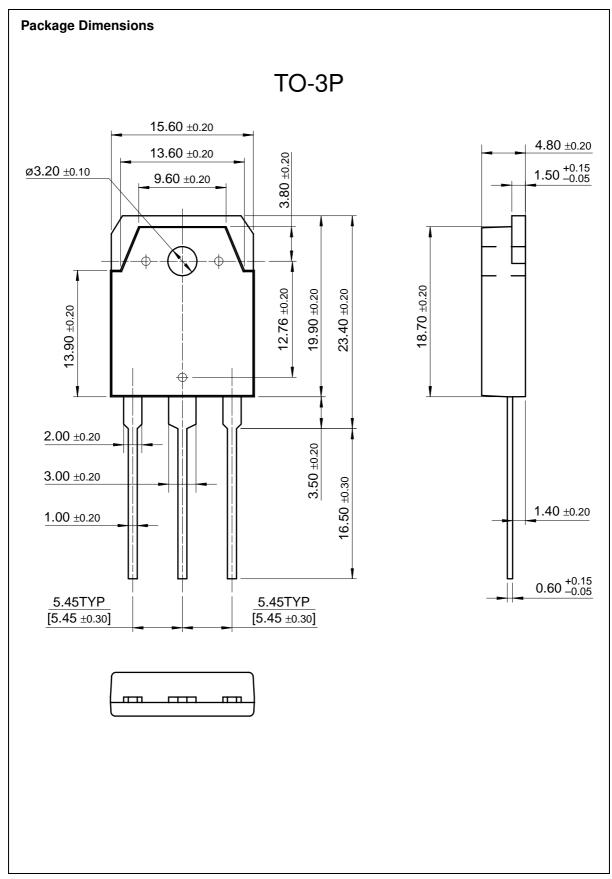




Body Diode Reverse Current



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